Search Notes

Application/Control No.	Applicant(s)/Patent u Reexamination	nder
10/620,664	MARGULIES ET AL	•
Examiner	Art Unit	
Alan Faber	2651	

	SEARCHED		
Class	Subclass	Date	Examiner
NONE	NONE	7/21/2005	AF
			-

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
NONE	NONE	7/21/2005	AF

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor search-see search history printout	7/20/2005	AF
Interference search history printout	7/21/2005	AF
EAST(USPAT,PGPUB,EPO,JPO,DER WENT,IBMTDB)-SEE SEARCH HISTORY PRINTOUT	7/20/2005	AF
360/55,59,131,135(text searc h only- see search history printout)	7/21/2005	AF
428/694BM,BP,TM,TP,MM,EC,IS(text search only-see search history printout)	7/21/2005	AF
369/13.25,13.01,300,13.02,13.14,13.2 4(text search only-see search history printout)	7/21/2005	AF
369/13.35,13.38,13.39,13.41,13.4,13. 42(text search only-see search history printout)	7/21/2005	AF
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Search Notes (continued)



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NONE	NONE	7/21/2005	AF
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
NONE	NONE	7/21/2005	AF
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
•	DATE	EXMR
369/13.51,13.43,13.44,13.48,13.49(te xt search only-see search history printout)	7/21/2005	AF
10/620,542 all refs checked	7/20/2005	AF
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5,583,727 all US Pat. refs. checked	7/20/2005	AF
5,986,978 all US Pat. refs. checked	7/20/2005	AF
6,280,813 all US Pat. refs. checked	7/20/2005	AF
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